

Probe & Scanner Deficiencies Appearance in B-Mode Imaging

Heather L. Miller
CIRS, Inc.
Norfolk, VA

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AAPM Annual Meeting - Orlando

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Common Probe Failure Modes

- Loss of transducer elements
- Cracked crystals
- Loose backing or facing material
- Broken lens
- Flaws in transducer scan mechanism

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Common Scanner Failure Modes

- Electronic drift of pulser-receiver components
- Variation in output intensity and/or receiver gain
- Loose connections in beam former plug-in board
- Drift or failure in systems internal timing circuits
- Input power fluctuations
- Longer excitation pulse

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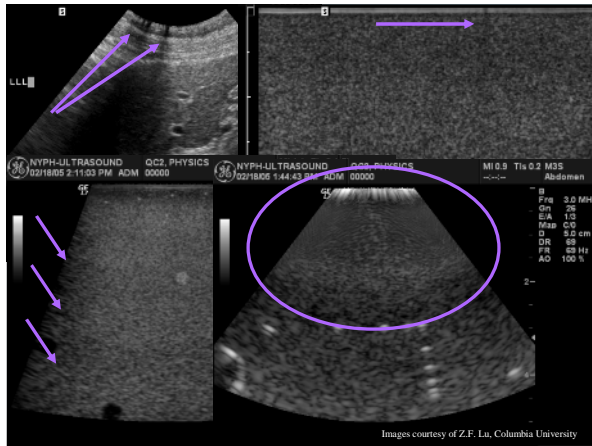
QA Measurements

- Depth of Penetration
- Image Uniformity
- Distance Measurements
- Axial Resolution
- Lateral Resolution
- Dead Zone

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Distance Measurements

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Distance Measurements

- Vertical
 - Drift or failure in system's internal timing circuits
- Horizontal
 - Flaws in transducer scan mechanism

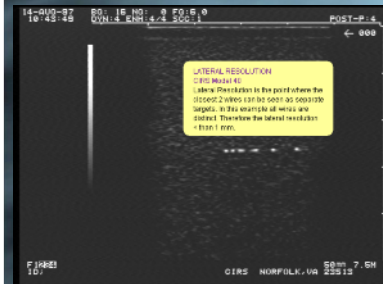
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Axial Resolution

- Damaged transducers
- Changes in pulser/receiver characteristics
- Changes in system setup

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Lateral Resolution



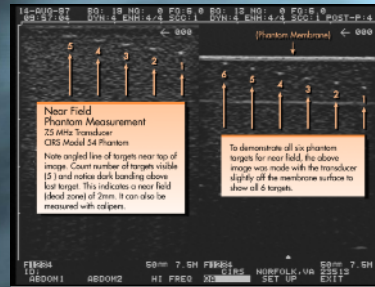
- Loss of transducer elements
- Problems in system's beam-forming and receiving circuits

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Dead Zone



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Dead Zone

- Elongated pulse length
- Cracked crystal
- Loose backing or facing material
- Broken lens
- Longer excitation pulse
- Input power fluctuations

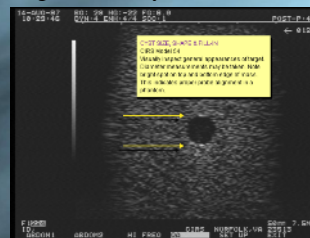
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Mass Resolution

Combination of spatial and contrast resolution and image uniformity



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Mass Resolution

- Electronic noise
- Side lobes in the transducer beam
- Problems in the image processing hardware

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